Renesas Electronics America Inc - R5F21272SNFP#V2 Datasheet

Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	R8C
Core Size	16-Bit
Speed	20MHz
Connectivity	I²C, LINbus, SIO, SSU, UART/USART
Peripherals	LED, POR, Voltage Detect, WDT
Number of I/O	25
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	512 x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 5.5V
Data Converters	A/D 12x10b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f21272snfp-v2

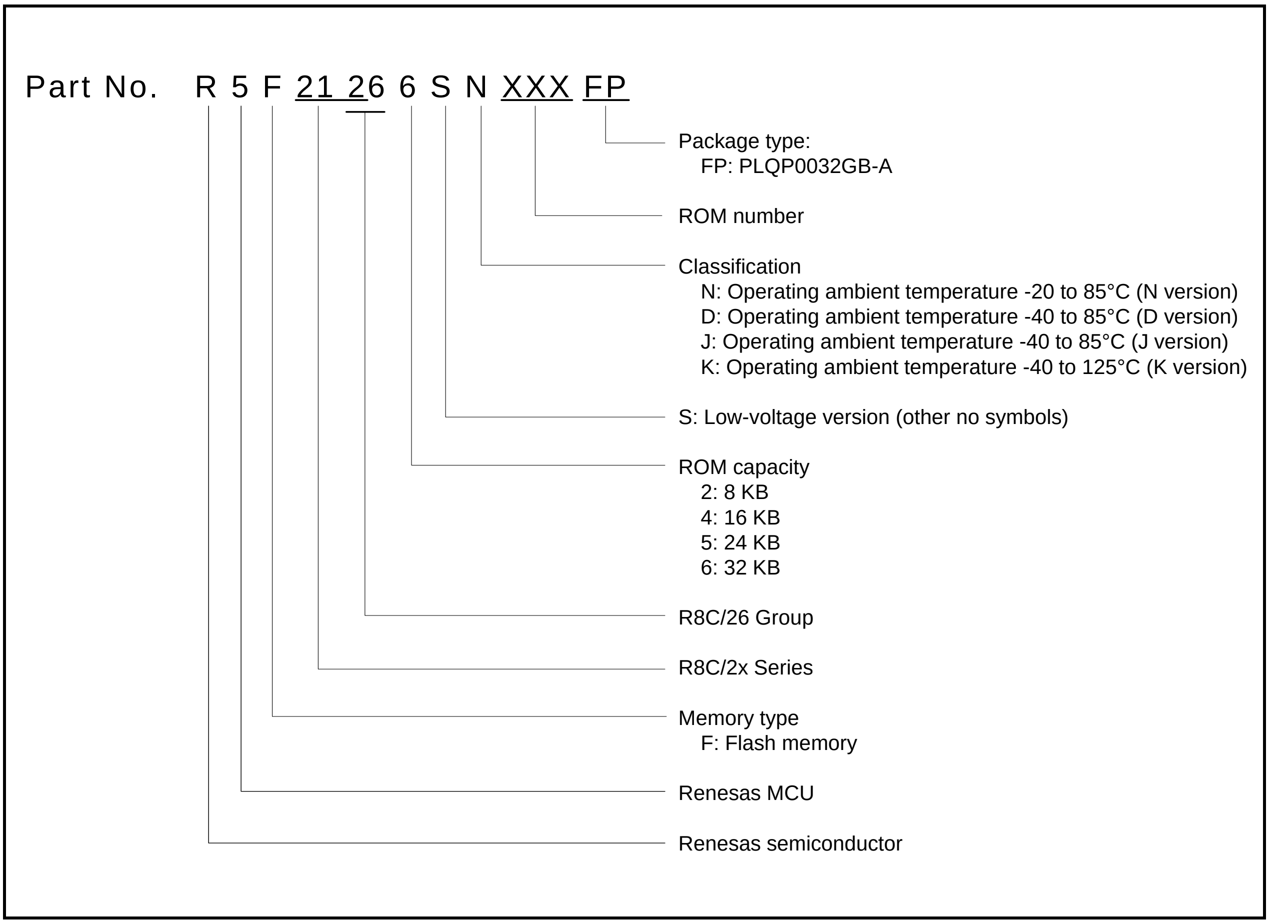
REJ03B0168-0210
Rev.2.10
Sep 26, 2008

1. Overview

These MCUs are fabricated using a high-performance silicon gate CMOS process, embedding the R8C CPU core, and are packaged in a 32-pin molded-plastic LQFP. It implements sophisticated instructions for a high level of instruction efficiency. With 1 Mbyte of address space, they are capable of executing instructions at high speed.
Furthermore, the R8C/27 Group has on-chip data flash (1 KB × 2 blocks).
The difference between the R8C/26 Group and R8C/27 Group is only the presence or absence of data flash.
Their peripheral functions are the same.

1.1 Applications

Electronic household appliances, office equipment, audio equipment, consumer products, automotive, etc.



Package type:
  FP: PLQP0032GB-A

ROM number

Classification
  N: Operating ambient temperature -20 to 85°C (N version)
  D: Operating ambient temperature -40 to 85°C (D version)
  J: Operating ambient temperature -40 to 85°C (J version)
  K: Operating ambient temperature -40 to 125°C (K version)

S: Low-voltage version (other no symbols)

ROM capacity
  2: 8 KB
  4: 16 KB
  5: 24 KB
  6: 32 KB

R8C/26 Group

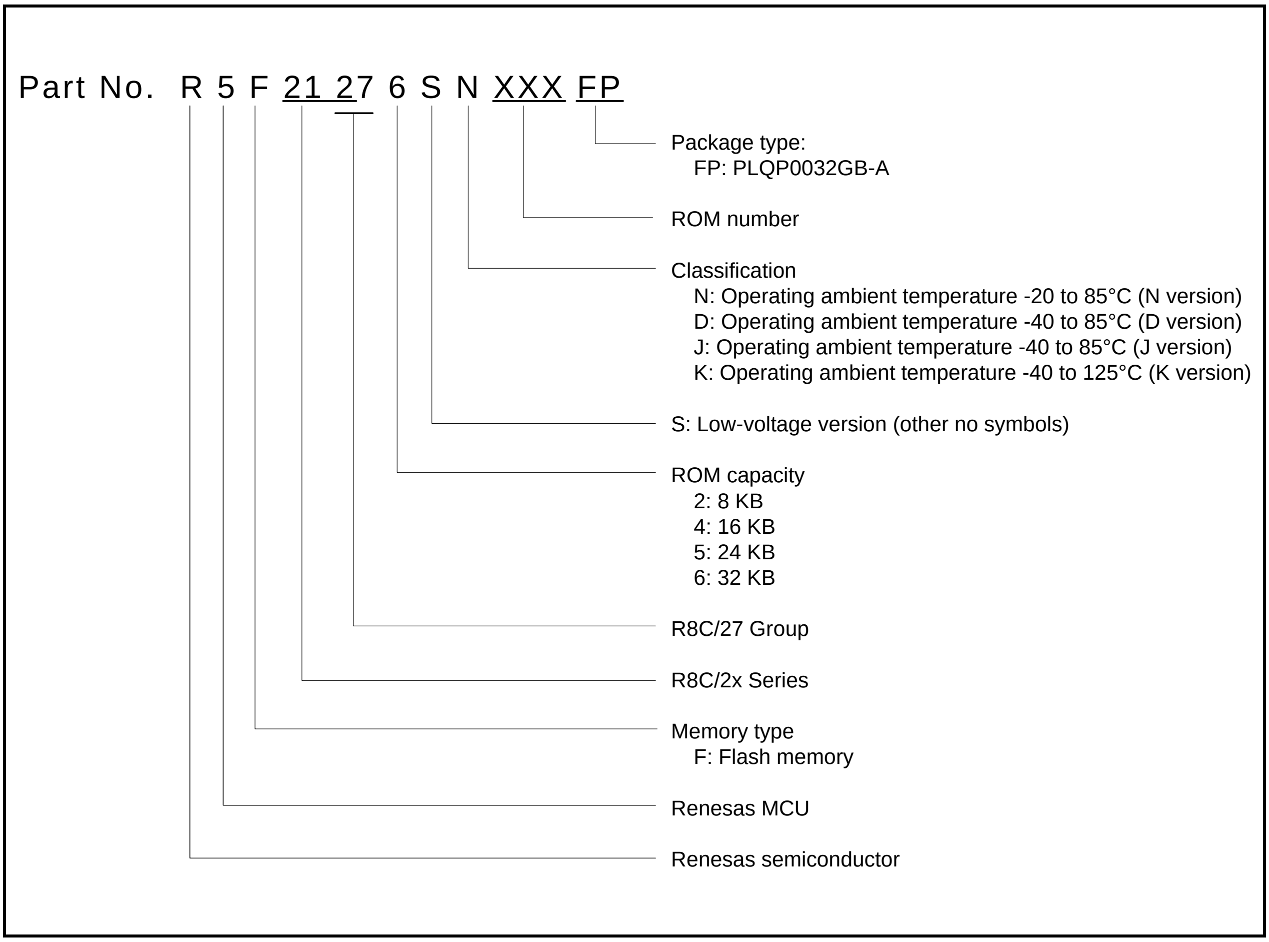
R8C/2x Series

Memory type
  F: Flash memory

Renesas MCU

Renesas semiconductor

Figure 1.2 Part Number, Memory Size, and Package of R8C/26 Group



Part No. R 5 F 21 27 6 S N XXX FP

Package type:
FP: PLQP0032GB-A

ROM number

Classification
N: Operating ambient temperature -20 to 85°C (N version)
D: Operating ambient temperature -40 to 85°C (D version)
J: Operating ambient temperature -40 to 85°C (J version)
K: Operating ambient temperature -40 to 125°C (K version)

S: Low-voltage version (other no symbols)

ROM capacity
2: 8 KB
4: 16 KB
5: 24 KB
6: 32 KB

R8C/27 Group

R8C/2x Series

Memory type
F: Flash memory

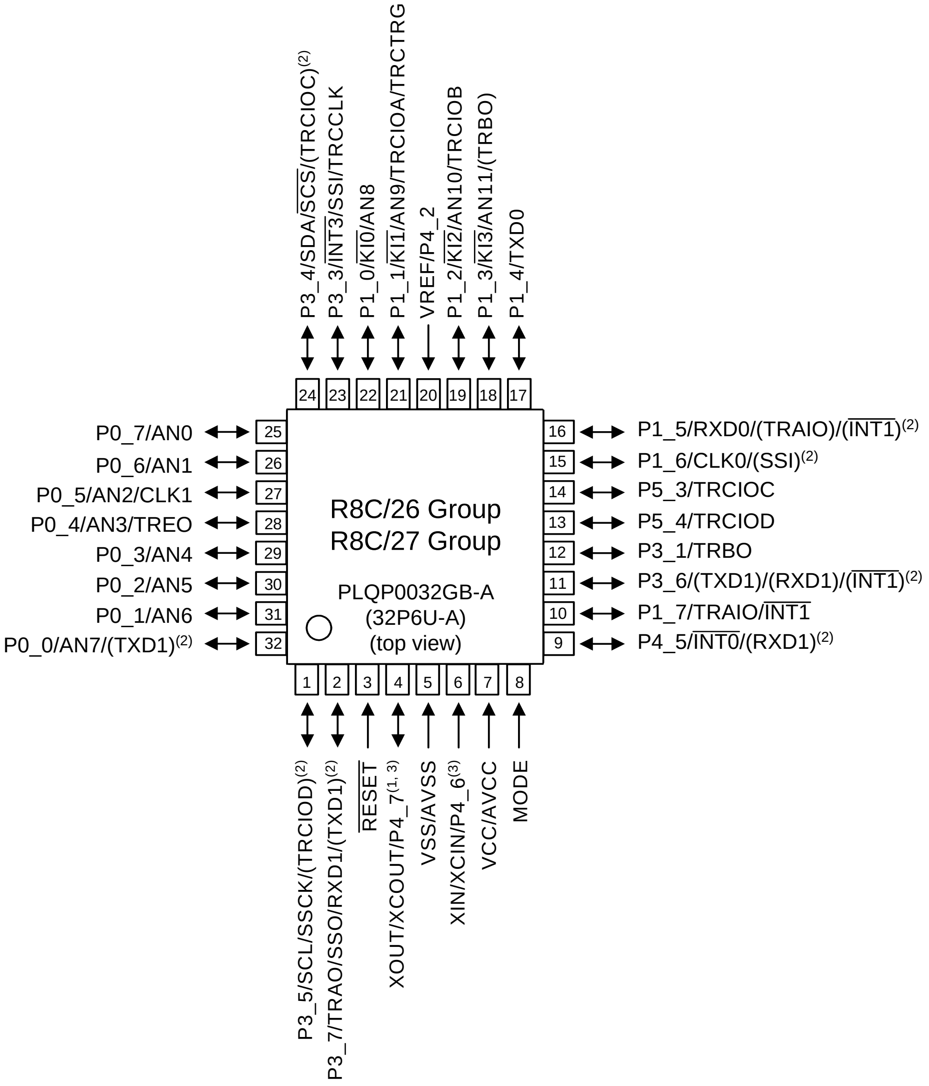
Renesas MCU

Renesas semiconductor

Figure 1.3 Part Number, Memory Size, and Package of R8C/27 Group

1.5 Pin Assignments

Figure 1.4 shows Pin Assignments (Top View).



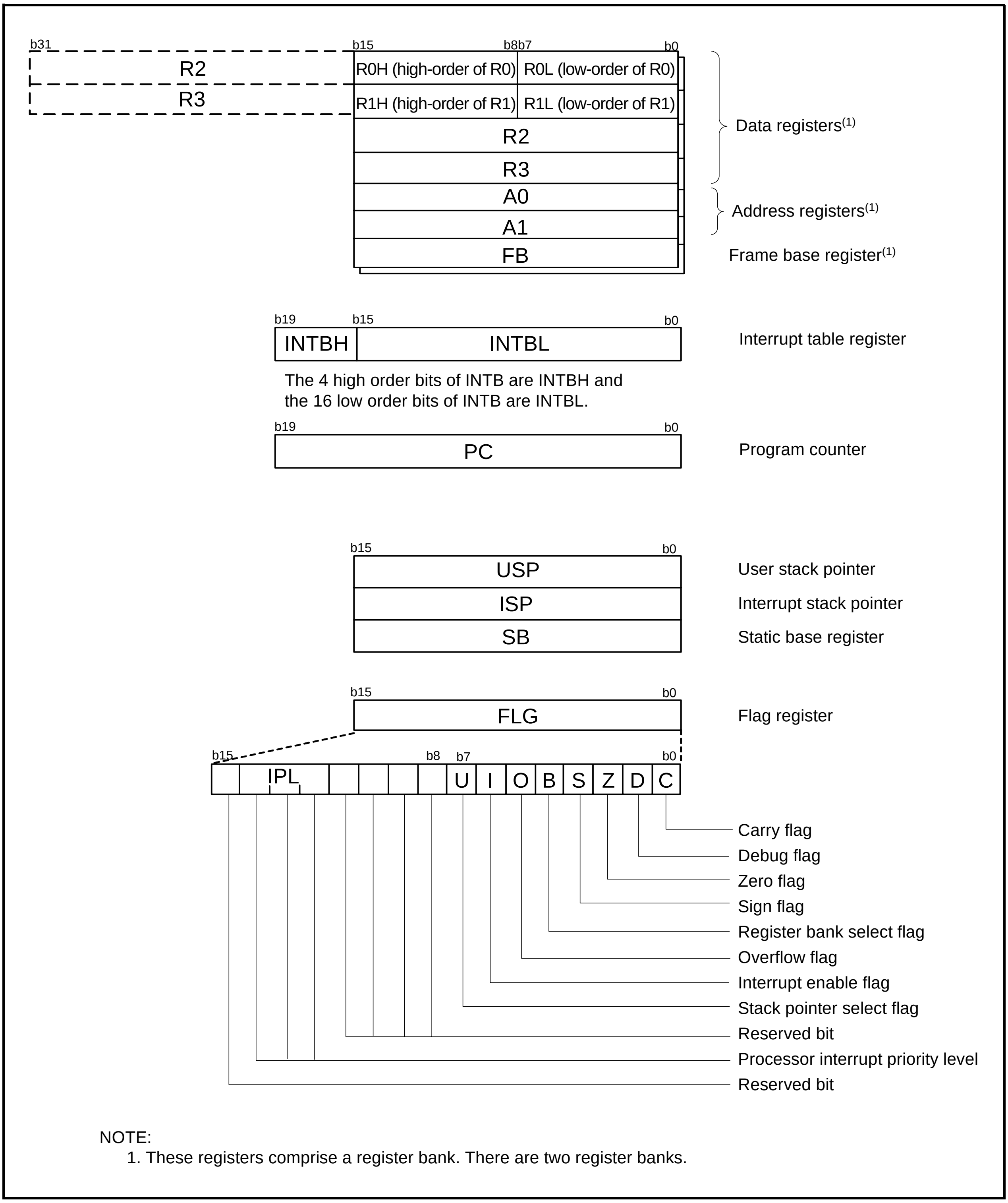
NOTES:

1. P4_7 is an input-only port.
2. Can be assigned to the pin in parentheses by a program.
3. XCIN, XCOUT can be used only for N or D version.
4. Confirm the pin 1 position on the package by referring to the package dimensions.

Figure 1.4 Pin Assignments (Top View)

2. Central Processing Unit (CPU)

Figure 2.1 shows the CPU Registers. The CPU contains 13 registers. R0, R1, R2, R3, A0, A1, and FB configure a register bank. There are two sets of register bank.



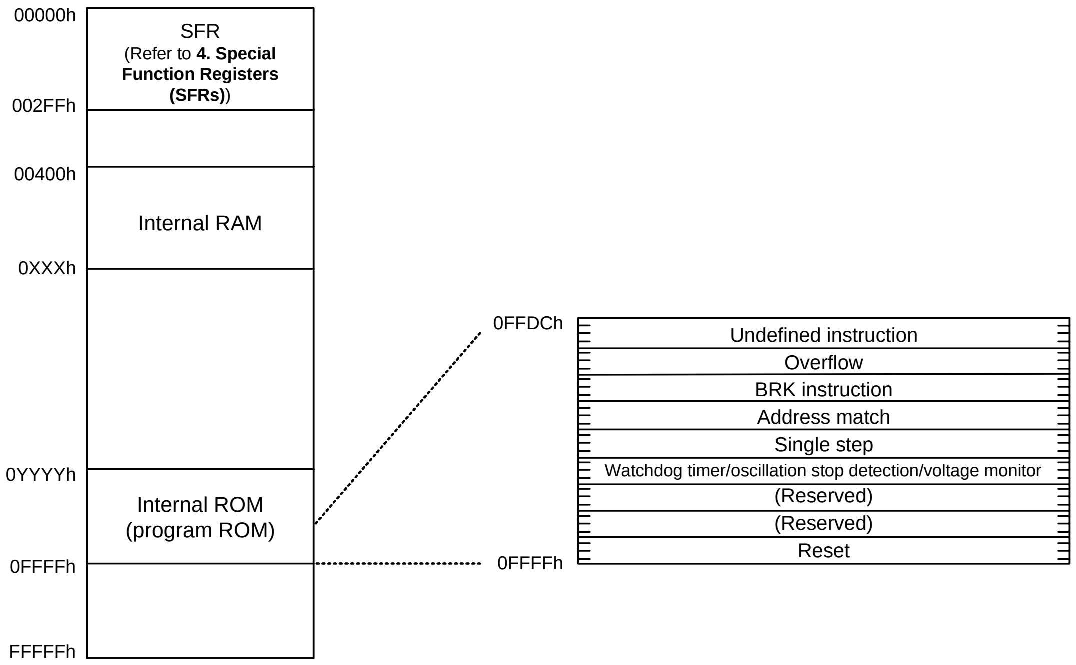
NOTE:
1. These registers comprise a register bank. There are two register banks.

Figure 2.1 CPU Registers

3. Memory

3.1 R8C/26 Group

Figure 3.1 is a Memory Map of R8C/26 Group. The R8C/26 group has 1 Mbyte of address space from addresses 00000h to FFFFFh.
The internal ROM is allocated lower addresses, beginning with address 0FFFFh. For example, a 16-Kbyte internal ROM area is allocated addresses 0C000h to 0FFFFh.
The fixed interrupt vector table is allocated addresses 0FFDCh to 0FFFFh. They store the starting address of each interrupt routine.
The internal RAM is allocated higher addresses beginning with address 00400h. For example, a 1-Kbyte internal RAM area is allocated addresses 00400h to 007FFh. The internal RAM is used not only for storing data but also for calling subroutines and as stacks when interrupt requests are acknowledged.
Special function registers (SFRs) are allocated addresses 00000h to 002FFh. The peripheral function control registers are allocated here. All addresses within the SFR, which have nothing allocated are reserved for future use and cannot be accessed by users.



NOTE:
1. The blank regions are reserved. Do not access locations in these regions.

Part Number	Internal ROM		Internal RAM	
	Size	Address 0YYYYh	Size	Address 0XXXXh
R5F21262SNFP, R5F21262SDFP, R5F21262SNXXXFP, R5F21262SDXXXFP	8 Kbytes	0E000h	512 bytes	005FFh
R5F21264SNFP, R5F21264SDFP, R5F21264JFP, R5F21264KFP, R5F21264SNXXXFP, R5F21264SDXXXFP, R5F21264JXXXFP, R5F21264KXXXFP	16 Kbytes	0C000h	1 Kbyte	007FFh
R5F21265SNFP, R5F21265SDFP R5F21265SNXXXFP, R5F21265SDXXXFP	24 Kbytes	0A000h	1.5 Kbytes	009FFh
R5F21266SNFP, R5F21266SDFP, R5F21266JFP, R5F21266KFP, R5F21266SNXXXFP, R5F21266SDXXXFP, R5F21266JXXXFP, R5F21266KXXXFP	32 Kbytes	08000h	1.5 Kbytes	009FFh

Figure 3.1 Memory Map of R8C/26 Group

3.2 R8C/27 Group

Figure 3.2 is a Memory Map of R8C/27 Group. The R8C/27 group has 1 Mbyte of address space from addresses 00000h to FFFFFh.

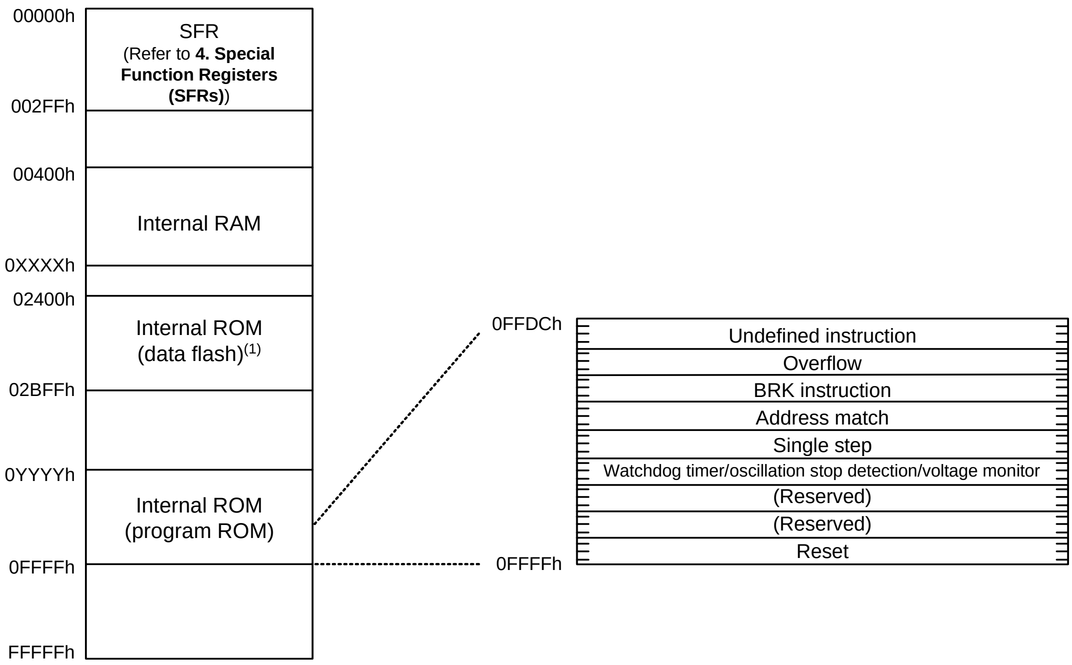
The internal ROM (program ROM) is allocated lower addresses, beginning with address 0FFFFh. For example, a 16-Kbyte internal ROM area is allocated addresses 0C000h to 0FFFFh.

The fixed interrupt vector table is allocated addresses 0FFDCh to 0FFFFh. They store the starting address of each interrupt routine.

The internal ROM (data flash) is allocated addresses 02400h to 02BFFh.

The internal RAM area is allocated higher addresses, beginning with address 00400h. For example, a 1-Kbyte internal RAM is allocated addresses 00400h to 007FFh. The internal RAM is used not only for storing data but also for calling subroutines and as stacks when interrupt requests are acknowledged.

Special function registers (SFRs) are allocated addresses 00000h to 002FFh. The peripheral function control registers are allocated here. All addresses within the SFR, which have nothing allocated are reserved for future use and cannot be accessed by users.



NOTES:
1. Data flash block A (1 Kbyte) and B (1 Kbyte) are shown.
2. The blank regions are reserved. Do not access locations in these regions.

Part Number	Internal ROM		Internal RAM	
	Size	Address 0YYYYh	Size	Address 0XXXXh
R5F21272SNFP, R5F21272SDFP, R5F21272SNXXXFP, R5F21272SDXXXFP	8 Kbytes	0E000h	512 bytes	005FFh
R5F21274SNFP, R5F21274SDFP, R5F21274JFP, R5F21274KFP, R5F21274SNXXXFP, R5F21274SDXXXFP, R5F21274JXXXFP, R5F21274KXXXFP	16 Kbytes	0C000h	1 Kbyte	007FFh
R5F21275SNFP, R5F21275SDFP, R5F21275SNXXXFP, R5F21275SDXXXFP	24 Kbytes	0A000h	1.5 Kbytes	009FFh
R5F21276SNFP, R5F21276SDFP, R5F21276JFP, R5F21276KFP, R5F21276SNXXXFP, R5F21276SDXXXFP, R5F21276JXXXFP, R5F21276KXXXFP	32 Kbytes	08000h	1.5 Kbytes	009FFh

Figure 3.2 Memory Map of R8C/27 Group

Table 5.3 A/D Converter Characteristics

Symbol	Parameter		Conditions	Standard			Unit
				Min.	Typ.	Max.	
–	Resolution		$V_{ref} = AV_{CC}$	–	–	10	Bits
–	Absolute accuracy	10-bit mode	ϕ_{AD} = 10 MHz, $V_{ref} = AV_{CC}$ = 5.0 V	–	–	±3	LSB
		8-bit mode	ϕ_{AD} = 10 MHz, $V_{ref} = AV_{CC}$ = 5.0 V	–	–	±2	LSB
		10-bit mode	ϕ_{AD} = 10 MHz, $V_{ref} = AV_{CC}$ = 3.3 V	–	–	±5	LSB
		8-bit mode	ϕ_{AD} = 10 MHz, $V_{ref} = AV_{CC}$ = 3.3 V	–	–	±2	LSB
		10-bit mode	ϕ_{AD} = 5 MHz, $V_{ref} = AV_{CC}$ = 2.2 V	–	–	±5	LSB
		8-bit mode	ϕ_{AD} = 5 MHz, $V_{ref} = AV_{CC}$ = 2.2 V	–	–	±2	LSB
R_{ladder}	Resistor ladder		$V_{ref} = AV_{CC}$	10	–	40	kΩ
t_{conv}	Conversion time	10-bit mode	ϕ_{AD} = 10 MHz, $V_{ref} = AV_{CC}$ = 5.0 V	3.3	–	–	µs
		8-bit mode	ϕ_{AD} = 10 MHz, $V_{ref} = AV_{CC}$ = 5.0 V	2.8	–	–	µs
V_{ref}	Reference voltage			2.2	–	AV_{CC}	V
V_{IA}	Analog input voltage(2)			0	–	AV_{CC}	V
–	A/D operating clock frequency	Without sample and hold	$V_{ref} = AV_{CC}$ = 2.7 to 5.5 V	0.25	–	10	MHz
		With sample and hold	$V_{ref} = AV_{CC}$ = 2.7 to 5.5 V	1	–	10	MHz
		Without sample and hold	$V_{ref} = AV_{CC}$ = 2.2 to 5.5 V	0.25	–	5	MHz
		With sample and hold	$V_{ref} = AV_{CC}$ = 2.2 to 5.5 V	1	–	5	MHz

NOTES:
1. AV_{CC} = 2.2 to 5.5 V at T_{opr} = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. When the analog input voltage is over the reference voltage, the A/D conversion result will be 3FFh in 10-bit mode and FFh in 8-bit mode.

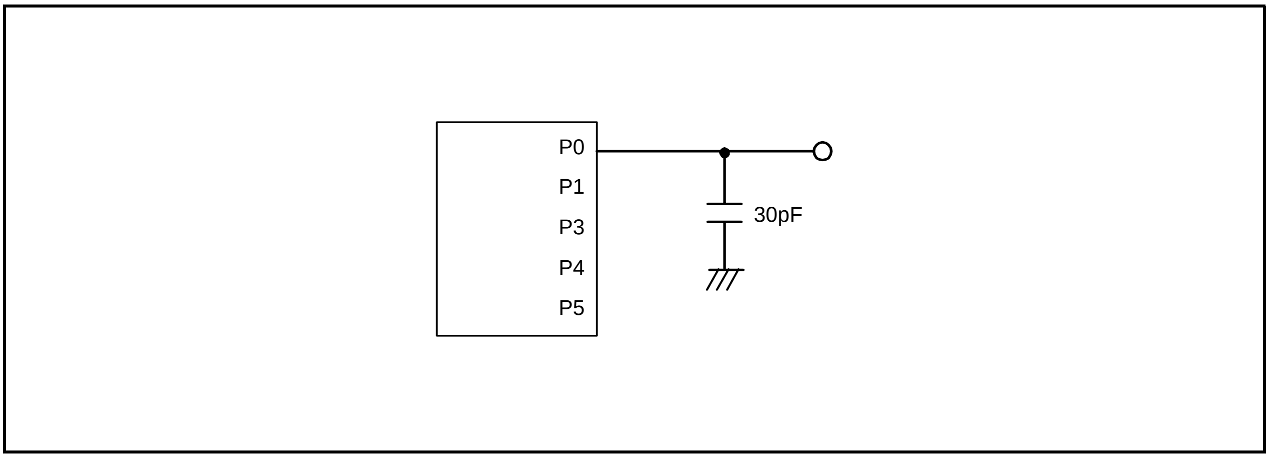


Figure 5.1 Ports P0, P1, and P3 to P5 Timing Measurement Circuit

Table 5.5 Flash Memory (Data flash Block A, Block B) Electrical Characteristics(4)

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
–	Program/erase endurance(2)		10,000(3)	–	–	times
–	Byte program time (program/erase endurance ≤ 1,000 times)		–	50	400	µs
–	Byte program time (program/erase endurance > 1,000 times)		–	65	–	µs
–	Block erase time (program/erase endurance ≤ 1,000 times)		–	0.2	9	s
–	Block erase time (program/erase endurance > 1,000 times)		–	0.3	–	s
$t_{d(SR-SUS)}$	Time delay from suspend request until suspend		–	–	97 + CPU clock × 6 cycles	µs
–	Interval from erase start/restart until following suspend request		650	–	–	µs
–	Interval from program start/restart until following suspend request		0	–	–	ns
–	Time from suspend until program/erase restart		–	–	3 + CPU clock × 4 cycles	µs
–	Program, erase voltage		2.7	–	5.5	V
–	Read voltage		2.2	–	5.5	V
–	Program, erase temperature		-20(8)	–	85	°C
–	Data hold time(9)	Ambient temperature = 55°C	20	–	–	year

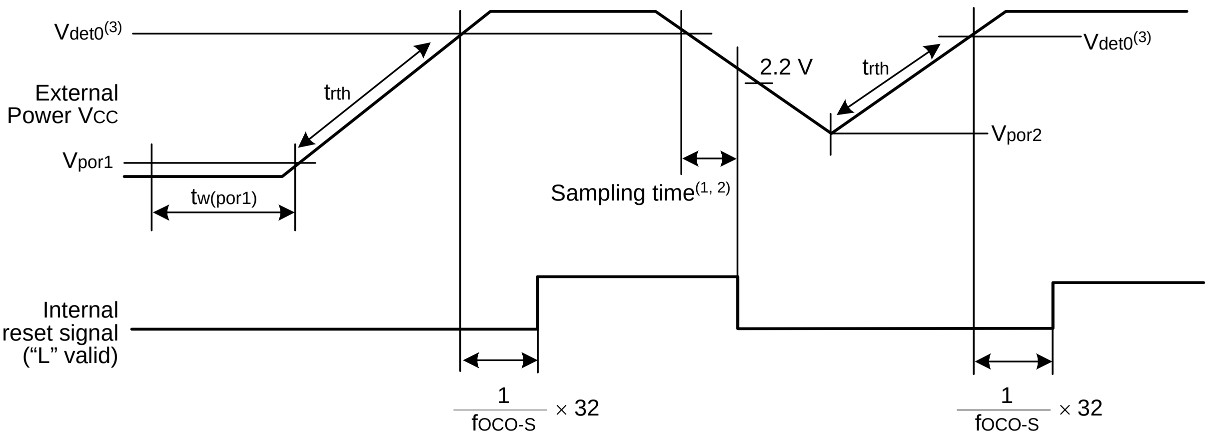
NOTES:

1. V_{CC} = 2.7 to 5.5 V at T_{opr} = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. Definition of programming/erasure endurance
   The programming and erasure endurance is defined on a per-block basis.
   If the programming and erasure endurance is n (n = 10,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one.
   However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
4. Standard of block A and block B when program and erase endurance exceeds 1,000 times. Byte program time to 1,000 times is the same as that in program ROM.
5. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. In addition, averaging the erasure endurance between blocks A and B can further reduce the actual erasure endurance. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
6. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
7. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
8. -40°C for D version.
9. The data hold time includes time that the power supply is off or the clock is not supplied.

Table 5.9 Power-on Reset Circuit, Voltage Monitor 0 Reset Electrical Characteristics[3]

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V_{por1}	Power-on reset valid voltage[4]		–	–	0.1	V
V_{por2}	Power-on reset or voltage monitor 0 reset valid voltage		0	–	V_{det0}	V
t_{rth}	External power V_{CC} rise gradient[2]		20	–	–	mV/msec

NOTES:
1. The measurement condition is T_{opr} = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. This condition (external power V_{CC} rise gradient) does not apply if $V_{CC} \geq 1.0$ V.
3. To use the power-on reset function, enable voltage monitor 0 reset by setting the LVD0ON bit in the OFS register to 0, the VW0C0 and VW0C6 bits in the VW0C register to 1 respectively, and the VCA25 bit in the VCA2 register to 1.
4. $t_{w(por1)}$ indicates the duration the external power V_{CC} must be held below the effective voltage (V_{por1}) to enable a power on reset. When turning on the power for the first time, maintain $t_{w(por1)}$ for 30 s or more if $-20°C \leq T_{opr} \leq 85°C$, maintain $t_{w(por1)}$ for 3,000 s or more if $-40°C \leq T_{opr} < -20°C$.



NOTES:
1. When using the voltage monitor 0 digital filter, ensure that the voltage is within the MCU operation voltage range (2.2 V or above) during the sampling time.
2. The sampling clock can be selected. Refer to **6. Voltage Detection Circuit** of Hardware Manual for details.
3. V_{det0} indicates the voltage detection level of the voltage detection 0 circuit. Refer to **6. Voltage Detection Circuit** of Hardware Manual for details.

Figure 5.3 Reset Circuit Electrical Characteristics

Table 5.10 High-speed On-Chip Oscillator Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
fOCO40M	High-speed on-chip oscillator frequency temperature • supply voltage dependence	V_{CC} = 4.75 to 5.25 V 0°C ≤ T_{opr} ≤ 60°C(2)	39.2	40	40.8	MHz
		V_{CC} = 3.0 to 5.5 V -20°C ≤ T_{opr} ≤ 85°C(2)	38.8	40	41.2	MHz
		V_{CC} = 3.0 to 5.5 V -40°C ≤ T_{opr} ≤ 85°C(2)	38.4	40	41.6	MHz
		V_{CC} = 2.7 to 5.5 V -20°C ≤ T_{opr} ≤ 85°C(2)	38	40	42	MHz
		V_{CC} = 2.7 to 5.5 V -40°C ≤ T_{opr} ≤ 85°C(2)	37.6	40	42.4	MHz
		V_{CC} = 2.2 to 5.5 V -20°C ≤ T_{opr} ≤ 85°C(3)	35.2	40	44.8	MHz
		V_{CC} = 2.2 to 5.5 V -40°C ≤ T_{opr} ≤ 85°C(3)	34	40	46	MHz
		V_{CC} = 5.0 V ± 10% -20°C ≤ T_{opr} ≤ 85°C(2)	38.8	40	40.8	MHz
		V_{CC} = 5.0 V ± 10% -40°C ≤ T_{opr} ≤ 85°C(2)	38.4	40	40.8	MHz
	High-speed on-chip oscillator frequency when correction value in FRA7 register is written to FRA1 register(4)	V_{CC} = 5.0 V, T_{opr} = 25°C	–	36.864	–	MHz
		V_{CC} = 3.0 to 5.5 V -20°C ≤ T_{opr} ≤ 85°C	-3%	–	3%	%
–	Value in FRA1 register after reset		08h(3)	–	F7h(3)	–
–	Oscillation frequency adjustment unit of high-speed on-chip oscillator	Adjust FRA1 register (value after reset) to -1	–	+0.3	–	MHz
–	Oscillation stability time		–	10	100	µs
–	Self power consumption at oscillation	V_{CC} = 5.0 V, T_{opr} = 25°C	–	400	–	µA

NOTES:

1. V_{CC} = 2.2 to 5.5 V, T_{opr} = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.
2. These standard values show when the FRA1 register value after reset is assumed.
3. These standard values show when the corrected value of the FRA6 register is written to the FRA1 register.
4. This enables the setting errors of bit rates such as 9600 bps and 38400 bps to be 0% when the serial interface is used in UART mode.

Table 5.11 Low-speed On-Chip Oscillator Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
fOCO-S	Low-speed on-chip oscillator frequency		30	125	250	kHz
–	Oscillation stability time		–	10	100	µs
–	Self power consumption at oscillation	V_{CC} = 5.0 V, T_{opr} = 25°C	–	15	–	µA

NOTE:

1. V_{CC} = 2.2 to 5.5 V, T_{opr} = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.

Table 5.12 Power Supply Circuit Timing Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
$t_{d(P-R)}$	Time for internal power supply stabilization during power-on(2)		1	–	2000	µs
$t_{d(R-S)}$	STOP exit time(3)		–	–	150	µs

NOTES:

1. The measurement condition is V_{CC} = 2.2 to 5.5 V and T_{opr} = 25°C.
2. Waiting time until the internal power supply generation circuit stabilizes during power-on.
3. Time until system clock supply starts after the interrupt is acknowledged to exit stop mode.

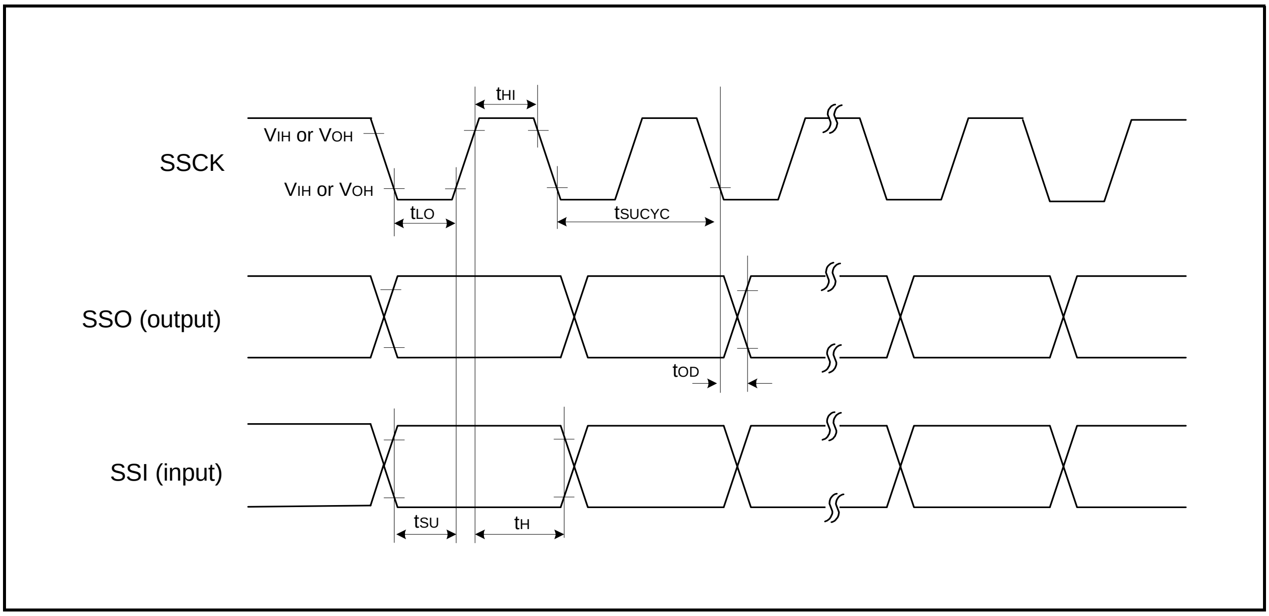


Figure 5.6 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Clock Synchronous Communication Mode)

Table 5.17 Electrical Characteristics (3) [Vcc = 5 V] (Topr = -20 to 85°C (N version) / -40 to 85°C (D version), unless otherwise specified.)

Symbol	Parameter	Condition		Standard			Unit
				Min.	Typ.	Max.	
ICC	Power supply current (VCC = 3.3 to 5.5 V) Single-chip mode, output pins are open, other pins are VSS	Wait mode	XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock operation VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	25	75	µA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator on = 125 kHz While a WAIT instruction is executed Peripheral clock off VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	23	60	µA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz (high drive) While a WAIT instruction is executed VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	4.0	–	µA
			XIN clock off High-speed on-chip oscillator off Low-speed on-chip oscillator off XCIN clock oscillator on = 32 kHz (low drive) While a WAIT instruction is executed VCA27 = VCA26 = VCA25 = 0 VCA20 = 1	–	2.2	–	µA
		Stop mode	XIN clock off, Topr = 25°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	–	0.8	3.0	µA
			XIN clock off, Topr = 85°C High-speed on-chip oscillator off Low-speed on-chip oscillator off CM10 = 1 Peripheral clock off VCA27 = VCA26 = VCA25 = 0	–	1.2	–	µA

Table 5.37 Flash Memory (Program ROM) Electrical Characteristics

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
–	Program/erase endurance(2)	R8C/26 Group	100(3)	–	–	times
		R8C/27 Group	1,000(3)	–	–	times
–	Byte program time		–	50	400	µs
–	Block erase time		–	0.4	9	s
$t_{d(SR-SUS)}$	Time delay from suspend request until suspend		–	–	97 + CPU clock × 6 cycles	µs
–	Interval from erase start/restart until following suspend request		650	–	–	µs
–	Interval from program start/restart until following suspend request		0	–	–	ns
–	Time from suspend until program/erase restart		–	–	3 + CPU clock × 4 cycles	µs
–	Program, erase voltage		2.7	–	5.5	V
–	Read voltage		2.7	–	5.5	V
–	Program, erase temperature		0	–	60	°C
–	Data hold time(7)	Ambient temperature = 55°C	20	–	–	year

NOTES:

1. V_{CC} = 2.7 to 5.5 V at T_{opr} = 0 to 60°C, unless otherwise specified.
2. Definition of programming/erasure endurance
   The programming and erasure endurance is defined on a per-block basis.
   If the programming and erasure endurance is n (n = 100 or 1,000), each block can be erased n times. For example, if 1,024 1-byte writes are performed to different addresses in block A, a 1 Kbyte block, and then the block is erased, the programming/erasure endurance still stands at one.
   However, the same address must not be programmed more than once per erase operation (overwriting prohibited).
3. Endurance to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
4. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 128 groups before erasing them all in one operation. It is also advisable to retain data on the erasure endurance of each block and limit the number of erase operations to a certain number.
5. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
6. Customers desiring program/erase failure rate information should contact their Renesas technical support representative.
7. The data hold time includes time that the power supply is off or the clock is not supplied.

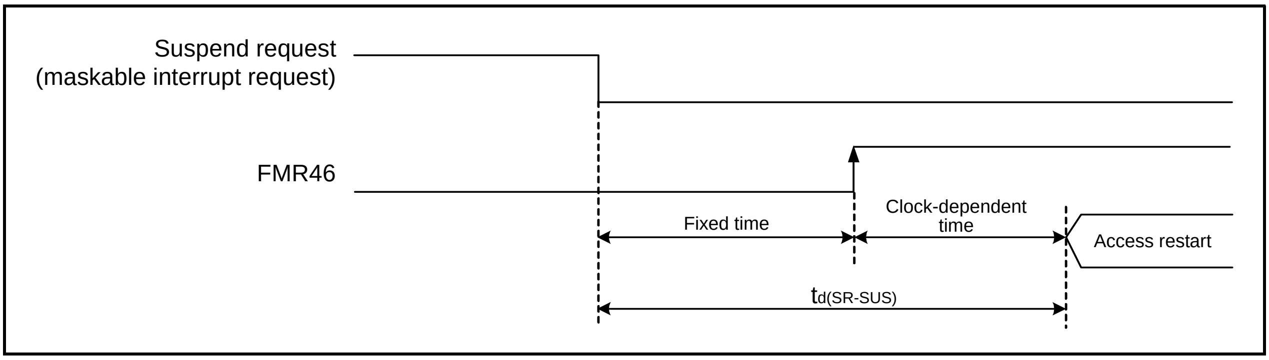


Figure 5.21 Time delay until Suspend

Table 5.39 Voltage Detection 1 Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V_{det1}	Voltage detection level[2, 4]		2.70	2.85	3.0	V
$t_{d(Vdet1-A)}$	Voltage monitor 1 reset generation time[5]		–	40	200	µs
–	Voltage detection circuit self power consumption	VCA26 = 1, V_{CC} = 5.0 V	–	0.6	–	µA
$t_{d(E-A)}$	Waiting time until voltage detection circuit operation starts[3]		–	–	100	µs
Vccmin	MCU operating voltage minimum value		2.70	–	–	V

NOTES:
1. The measurement condition is V_{CC} = 2.7 to 5.5 V and T_{opr} = -40 to 85°C (J version) / -40 to 125°C (K version).
2. Hold $V_{det2} > V_{det1}$.
3. Necessary time until the voltage detection circuit operates when setting to 1 again after setting the VCA26 bit in the VCA2 register to 0.
4. This parameter shows the voltage detection level when the power supply drops.
   The voltage detection level when the power supply rises is higher than the voltage detection level when the power supply drops by approximately 0.1 V.
5. Time until the voltage monitor 1 reset is generated after the voltage passes V_{det1} when V_{CC} falls. When using the digital filter, its sampling time is added to $t_{d(Vdet1-A)}$. When using the voltage monitor 1 reset, maintain this time until V_{CC} = 2.0 V after the voltage passes V_{det1} when the power supply falls.

Table 5.40 Voltage Detection 2 Circuit Electrical Characteristics

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V_{det2}	Voltage detection level[2]		3.3	3.6	3.9	V
$t_{d(Vdet2-A)}$	Voltage monitor 2 reset/interrupt request generation time[3, 5]		–	40	200	µs
–	Voltage detection circuit self power consumption	VCA27 = 1, V_{CC} = 5.0 V	–	0.6	–	µA
$t_{d(E-A)}$	Waiting time until voltage detection circuit operation starts[4]		–	–	100	µs

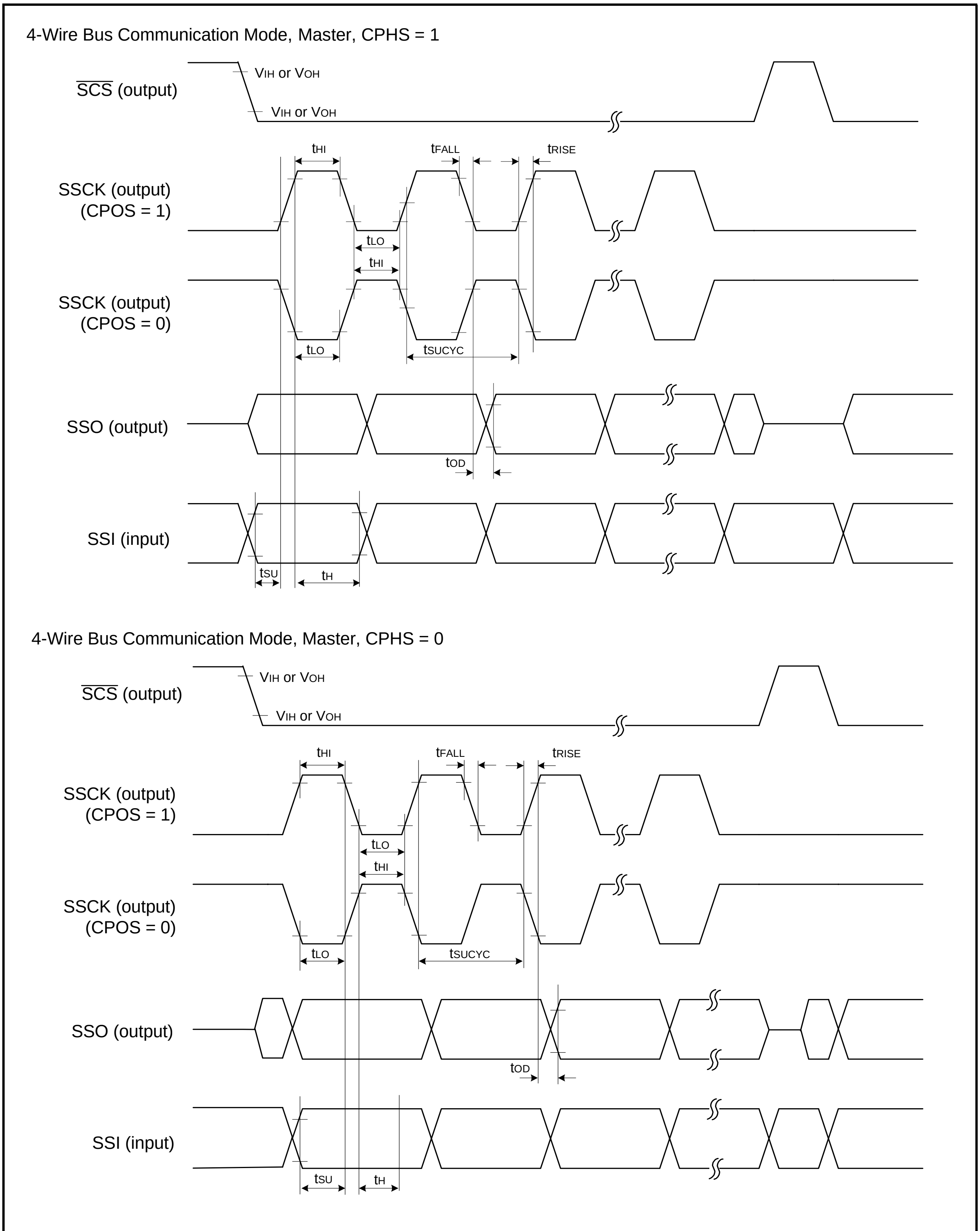
NOTES:
1. The measurement condition is V_{CC} = 2.7 to 5.5 V and T_{opr} = -40 to 85°C (J version) / -40 to 125°C (K version).
2. Hold $V_{det2} > V_{det1}$.
3. Time until the voltage monitor 2 reset/interrupt request is generated after the voltage passes V_{det2}.
4. Necessary time until the voltage detection circuit operates after setting to 1 again after setting the VCA27 bit in the VCA2 register to 0.
5. When using the digital filter, its sampling time is added to $t_{d(Vdet2-A)}$. When using the voltage monitor 2 reset, maintain this time until V_{CC} = 2.0 V after the voltage passes V_{det2} when the power supply falls.

Table 5.45 Timing Requirements of Clock Synchronous Serial I/O with Chip Select(1)

Symbol	Parameter		Conditions	Standard			Unit
				Min.	Typ.	Max.	
t_{SUCYC}	SSCK clock cycle time			4	–	–	t_{CYC}(2)
t_{HI}	SSCK clock “H” width			0.4	–	0.6	t_{SUCYC}
t_{LO}	SSCK clock “L” width			0.4	–	0.6	t_{SUCYC}
t_{RISE}	SSCK clock rising time	Master		–	–	1	t_{CYC}(2)
		Slave		–	–	1	μs
t_{FALL}	SSCK clock falling time	Master		–	–	1	t_{CYC}(2)
		Slave		–	–	1	μs
t_{SU}	SSO, SSI data input setup time			100	–	–	ns
t_{H}	SSO, SSI data input hold time			1	–	–	t_{CYC}(2)
t_{LEAD}	$\overline{SCS}$ setup time	Slave		$1t_{CYC} + 50$	–	–	ns
t_{LAG}	$\overline{SCS}$ hold time	Slave		$1t_{CYC} + 50$	–	–	ns
t_{OD}	SSO, SSI data output delay time			–	–	1	t_{CYC}(2)
t_{SA}	SSI slave access time			–	–	$1.5t_{CYC} + 100$	ns
t_{OR}	SSI slave out open time			–	–	$1.5t_{CYC} + 100$	ns

NOTES:

1. V_{CC} = 2.7 to 5.5 V, V_{SS} = 0 V at T_{opr} = -40 to 85°C (J version) / -40 to 125°C (K version), unless otherwise specified.
2. $1t_{CYC} = 1/f1(s)$



CPHS, CPOS: Bits in SSMR register

Figure 5.23 I/O Timing of Clock Synchronous Serial I/O with Chip Select (Master)

Timing requirements
(Unless Otherwise Specified: V_{CC} = 3 V, V_{SS} = 0 V at T_{opr} = 25°C) [V_{CC} = 3 V]

Table 5.55 XIN Input

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(XIN)}$	XIN input cycle time	100	–	ns
$t_{WH(XIN)}$	XIN input “H” width	40	–	ns
$t_{WL(XIN)}$	XIN input “L” width	40	–	ns

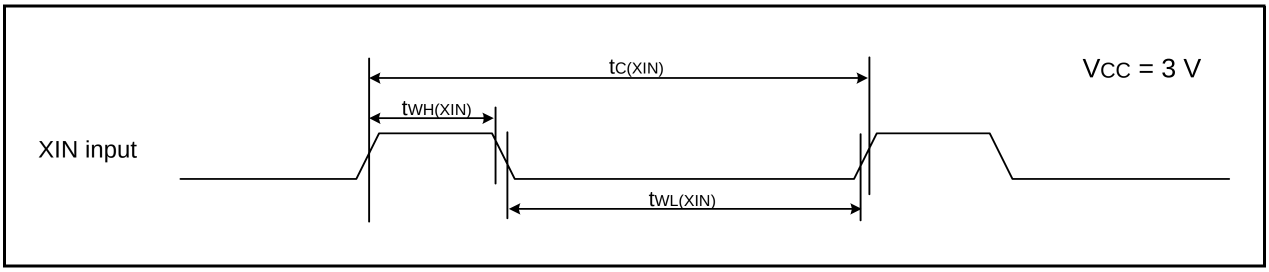


Figure 5.31 XIN Input Timing Diagram when V_{CC} = 3 V

Table 5.56 TRAIO Input

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(TRAIO)}$	TRAIO input cycle time	300	–	ns
$t_{WH(TRAIO)}$	TRAIO input “H” width	120	–	ns
$t_{WL(TRAIO)}$	TRAIO input “L” width	120	–	ns

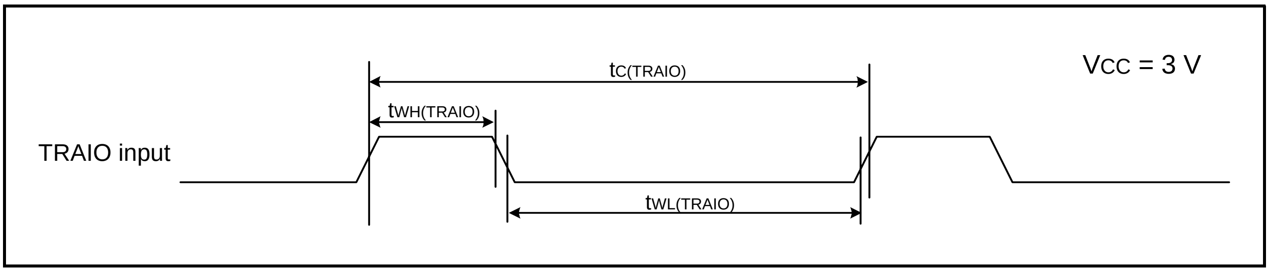


Figure 5.32 TRAIO Input Timing Diagram when V_{CC} = 3 V

REVISION HISTORY — R8C/26 Group, R8C/27 Group Datasheet

Rev.	Date	Description	
		Page	Summary
0.10	Nov 14, 2005	–	First edition issued
0.20	Feb 06, 2006	2, 3	Table 1.1 Functions and Specifications for R8C/26Group and Table 1.2 Functions and Specifications for R8C/27 Group; Minimum instruction execution time and Supply voltage revised
		9	Table 1.6 Pin Name Information by Pin Number; “XOUT” → “XOUT/XCOUT” and “XIN” → “XIN/XCIN” revised
		18	Table 4.4 SFR Information (4); 00FEh: “DRR” → “P1DRR” revised
		19	Table 4.5 SFR Information (5); -0119h: “Timer RE Minute Data Register / Compare Register” → “Timer RE Minute Data Register / Compare Data Register” -011Ah: “Timer RE Time Data Register” → “Timer RE Hour Data Register” -011Bh: “Timer RE Day Data Register” → “Timer RE Day of Week Data Register” revised
		22 to 45	5. Electrical Characteristics added
1.00	Nov 08, 2006	All pages	“Preliminary” deleted
		2	Table 1.1 revised
		3	Table 1.2 revised
		4	Figure 1.1 revised
		5	Table 1.3 revised
		6	Table 1.4 revised
		7	Figure 1.4 revised
		9	Table 1.6 revised
		15	Table 4.1; • 001Ch: “00h” → “00h, 10000000b” revised • 000Fh: “000XXXXXb” → “00X11111b” revised • 0029h: “High-Speed On-Chip Oscillator Control Register 4, FRA4, When shipping” added • 002Bh: “High-Speed On-Chip Oscillator Control Register 6, FRA6, When shipping” added • 0032h: “00h, 01000000b” → “00h, 00100000b” revised • 0038h: “00001000b, 01001001b” → “0000X000b, 0100X001b” revised • NOTE3 and 4 revised; NOTE6 added
		18	Table 4.4; • 00E0h, 00E1h, 00E5h, 00E8h, 00E9h: “XXh” → “00h” revised • 00FDh: “XX00000000b” → “00h” revised
		22	Table 5.2 revised
		23	Figure 5.1 title revised
		24	Table 5.4 revised
		25	Table 5.5 revised
		26	Figure 5.2 title revised and Table 5.7 NOTE4 added

REVISION HISTORY	R8C/26 Group, R8C/27 Group Datasheet

Rev.	Date	Description	
		Page	Summary
1.00	Nov 08, 2006	27	Table 5.9, Figure 5.3 revised and Table 5.10 deleted
		28	Table 5.10, Table 5.11 revised
		34	Table 5.15 revised
		35	Table 5.16 revised
		36	Table 5.17 revised
		39	Table 5.22 revised
		40	Table 5.23 revised
		44	Table 5.29 revised
		47	Package Dimensions; “Diagrams showing the latest...website.” added
1.10	Nov 29, 2006	All pages	“J, K version” added
		1	1 “J and K versions are under development...notice.” added 1.1 revised
		2	Table 1.1 revised
		3	Table 1.2 revised
		4	Figure 1.1 NOTE3 added
		5	Table 1.3, Figure 1.2 revised
		6	Table 1.4, Figure 1.3 revised
		7	Figure 1.4 NOTE3 added
		8	Table 1.5 revised
		9	Table 1.6 NOTE2 added
		13	Figure 3.1 revised
		14	Figure 3.2 revised
		15	Table 4.1; “0000h to 003Fh” → “0000h to 002Fh” revised • NOTE3 added
		16	Table 4.2; “0040h to 007Fh” → “0030h to 007Fh” revised • 0032h, 0036h: “After reset” is revised • 0038h: NOTE revised • NOTES 2, 5, 6 revised and NOTE 7, 8 added
		19	Table 4.5 NOTE2 added
		28	Table 5.10 revised
		48 to 66	5.2 J, K Version added
1.20	Jan 17, 2007	18	Table 4.4 NOTE2 added
1.30	May 25, 2007	2	Table 1.1 revised
		3	Table 1.2 revised
		5	Table 1.3 revised
		6	Figure 1.2 revised
		7	Table 1.4 revised
		8	Figure 1.3 revised
		9	Figure 1.4 NOTE4 added
		15	Figure 3.1 part number revised